

Search Notes

Application/Control No.

10/790,126

Examiner

HUYEN D. LE

Applicant(s)/Patent under
Reexamination

BAYER, ERICH

Art Unit

2615

SEARCHED

Class	Subclass	Date	Examiner
38	322, 330, 324-328, 380-382	12/19/2006	HL
181	129		HL
181	130		HL
181	135		HL
600	25		HL
600	559		HL
607	56, 57		HL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Same as above		12/19/2006	HL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR